

MAX3

Low Voltage Burn-in and Test System

For burning-in and testing DUTs such as
microprocessors, DSPs, and logic devices,
which require low voltage



System Features

- Output monitoring gives functional test results for every device during burn-in.
- Production capacity with 64 BIB positions
- Engineering/QA configurations with up to 32 independent pattern zones
- Lot control and device protection
- ATS and MAX burn-in board compatible

Signal and Bias Features

- 96 independent I/O channels
- Stimulus voltages as low as 0.7V
- Up to 24M pattern depth for BIST and JTAG applications
- 3 separate bias voltages per device

Software Features

- Windows 2000-based operation and programming
- Modular test-plan development for ease of programming
- DUT pass/fail BIB map
- Easy interface to sorting BIB unloaders

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